Microsemi Corporation - 5962-9322102MXA Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

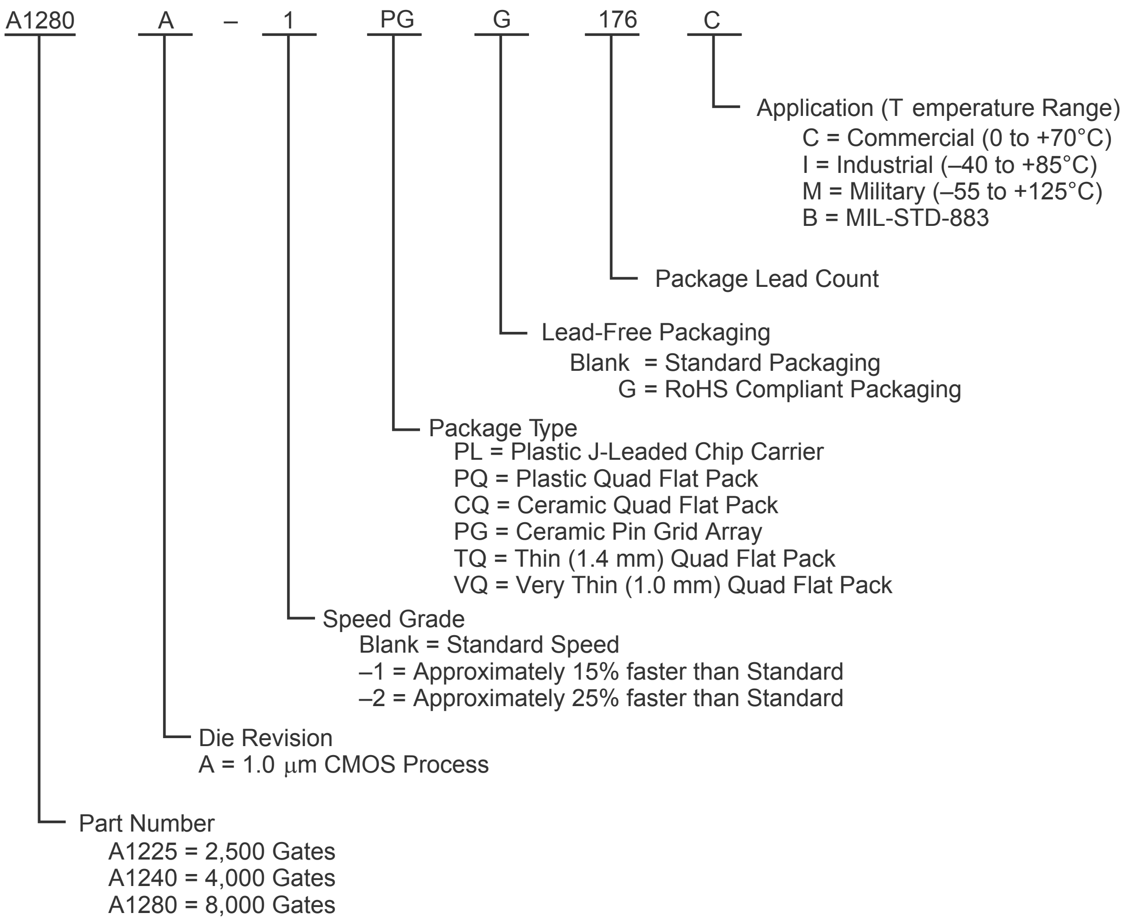
The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	684
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	104
Number of Gates	4000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	132-BCPGA
Supplier Device Package	132-CPGA (34.54x34.54)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/5962-9322102mxa

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Ordering Information



A1280 A – 1 PG G 176 C

Application (Temperature Range)
C = Commercial (0 to +70°C)
I = Industrial (–40 to +85°C)
M = Military (–55 to +125°C)
B = MIL-STD-883

Package Lead Count

Lead-Free Packaging
Blank = Standard Packaging
G = RoHS Compliant Packaging

Package Type
PL = Plastic J-Leaded Chip Carrier
PQ = Plastic Quad Flat Pack
CQ = Ceramic Quad Flat Pack
PG = Ceramic Pin Grid Array
TQ = Thin (1.4 mm) Quad Flat Pack
VQ = Very Thin (1.0 mm) Quad Flat Pack

Speed Grade
Blank = Standard Speed
–1 = Approximately 15% faster than Standard
–2 = Approximately 25% faster than Standard

Die Revision
A = 1.0 µm CMOS Process

Part Number
A1225 = 2,500 Gates
A1240 = 4,000 Gates
A1280 = 8,000 Gates

2 – Detailed Specifications

Operating Conditions

***Table 2-1* • Absolute Maximum Ratings[1]**

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current[2]	±20	mA
T_{STG}	Storage temperature	–65 to +150	°C

Notes:

1. *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.*
2. *Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will be forward biased and can draw excessive current.*

***Table 2-2* • Recommended Operating Conditions**

Parameter	Commercial	Industrial	Military	Units
Temperature range*	0 to +70	–40 to +85	–55 to +125	°C
Power supply tolerance	±5	±10	±10	%VCC

*Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.*

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. EQ 4 shows a piece-wise linear summation over all components.

$$\begin{aligned}\text{Power} =\, & VCC^2 * [(m * C_{EQM} * f_m)_{modules} + (n * C_{EQI} * f_n)_{inputs} \\ & + (p * (C_{EQO} + C_L) * fp)_{outputs} \\ & + 0.5 * (q1 * C_{EQCR} * f_{q1})_{routed\_Clk1} + (r1 * f_{q1})_{routed\_Clk1} \\ & + 0.5 * (q2 * C_{EQCR} * f_{q2})_{routed\_Clk2} + (r_2 * f_{q2})_{routed\_Clk2}\end{aligned}$$

EQ 4

Where:

m = Number of logic modules switching at f_m

n = Number of input buffers switching at f_n

p = Number of output buffers switching at f_p

q1 = Number of clock loads on the first routed array clock

q2 = Number of clock loads on the second routed array clock

r_1 = Fixed capacitance due to first routed array clock

r_2 = Fixed capacitance due to second routed array clock

C_{EQM} = Equivalent capacitance of logic modules in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of routed array clock in pF

C_L = Output lead capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

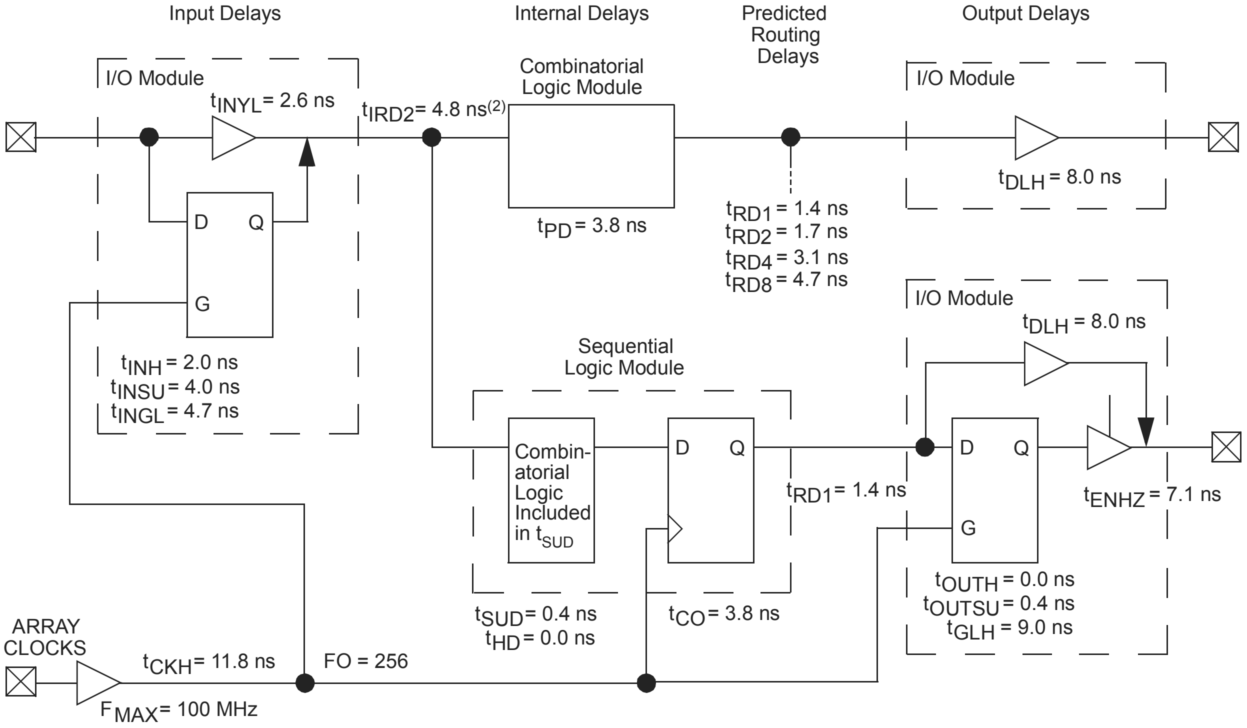
f_{q1} = Average first routed array clock rate in MHz

f_{q2} = Average second routed array clock rate in MHz

***Table 2-7* • Fixed Capacitance Values for Microsemi FPGAs**

Device Type	**r1, routed_Clk1**	**r2, routed_Clk2**
A1225A	106	106.0
A1240A	134	134.2
A1280A	168	167.8

ACT 2 Timing Model[1]



Notes:

1. *Values shown for A1240A-2 at worst-case commercial conditions.*
2. *Input module predicted routing delay*

Figure 2-1 • **Timing Model**

Parameter Measurement

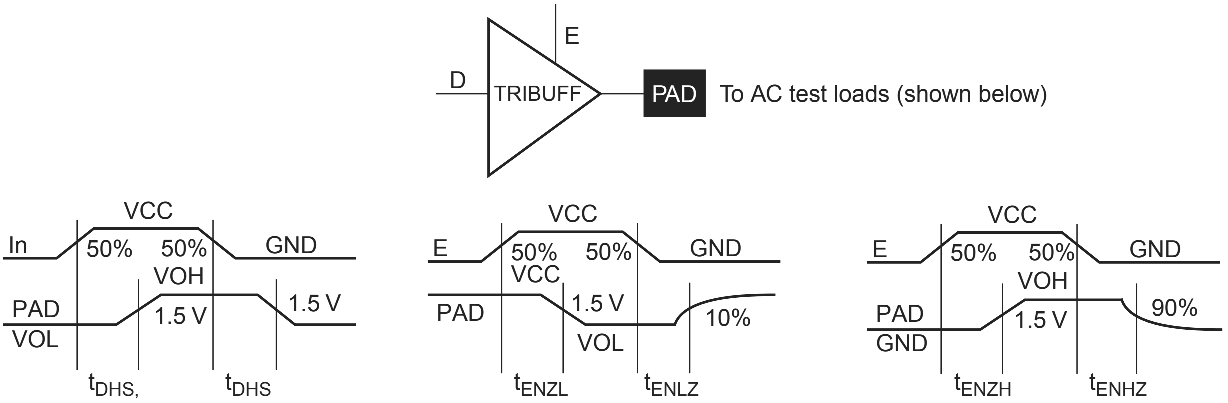


***Figure 2-2* •** **Output Buffer Delays**

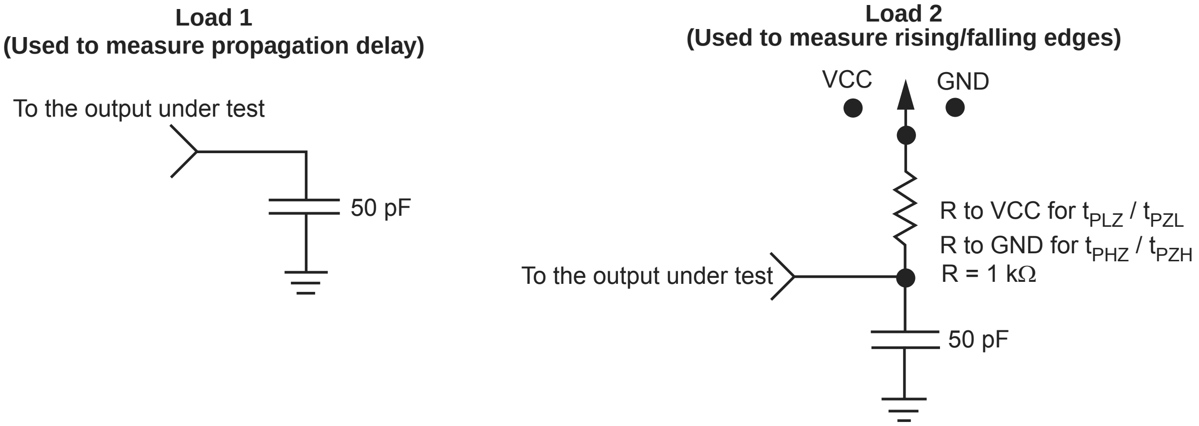


***Figure 2-3* •** **AC Test Loads**

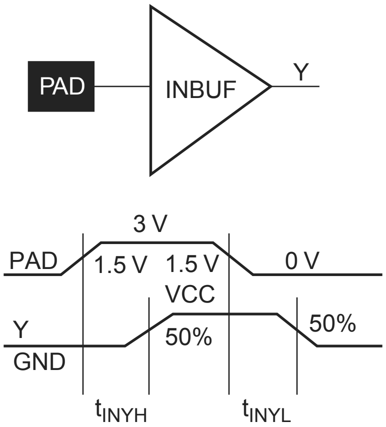


***Figure 2-4* •** **Input Buffer Delays**

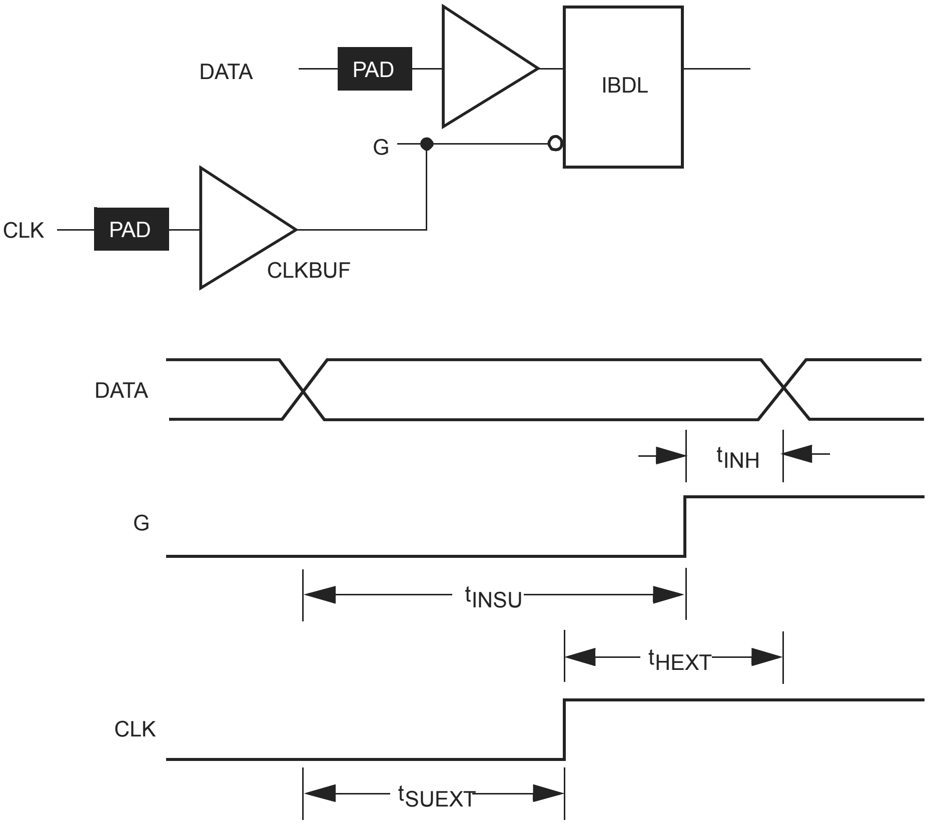


Figure 2-7 • **Input Buffer Latches**

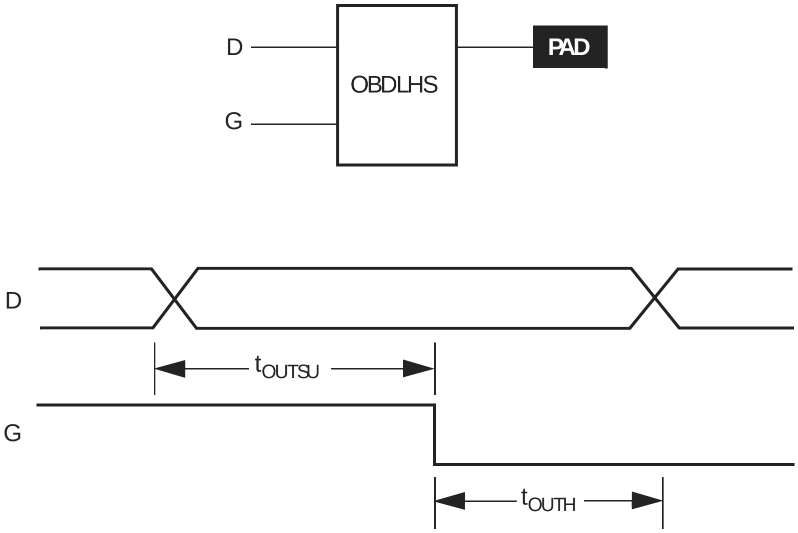


Figure 2-8 • **Output Buffer Latches**

Timing Derating Factor (Temperature and Voltage)

***Table 2-9* • Timing Derating Factor (Temperature and Voltage)**

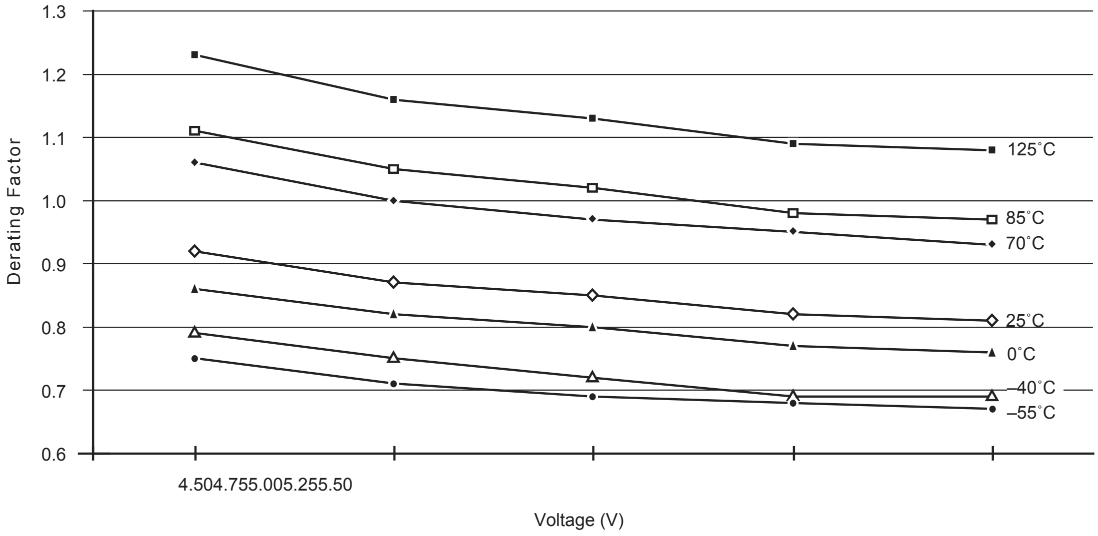
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	**Max.**	**Min.**	Max.
	0.69	1.11	0.67	1.23

***Table 2-10* • Timing Derating Factor for Designs at Typical Temperature (T_J = 25°C) and Voltage (5.0 V)**

(Commercial Maximum Specification) x	0.85

***Table 2-11* • Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial, TJ = 4.75 V, 70°C)**

	–55	**–40**	**0**	**25**	**70**	**85**	**125**
4.50	0.75	0.79	0.86	0.92	1.06	1.11	1.23
4.75	0.71	0.75	0.82	0.87	1.00	1.05	1.13
5.00	0.69	0.72	0.80	0.85	0.97	1.02	1.13
5.25	0.68	0.69	0.77	0.82	0.95	0.98	1.09
5.50	0.67	0.69	0.76	0.81	0.93	0.97	1.08



Note: This derating factor applies to all routing and propagation delays.

***Figure 2-9* • Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial, T_J = 4.75 V, 70°C)**

A1225A Timing Characteristics (continued)

***Table 2-14* • A1225A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

TTL Output Module Timing[1]		**–2 Speed**		**–1 Speed**		**Std. Speed**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{DLH}	Data to Pad High		8.0		9.0		10.6	ns
t_{DHL}	Data to Pad Low		10.1		11.4		13.4	ns
t_{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t_{ENZL}	Enable Pad Z to Low		11.6		13.2		15.5	ns
t_{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t_{ENLZ}	Enable Pad Low to Z		8.3		9.5		11.1	ns
t_{GLH}	G to Pad High		8.9		10.2		11.9	ns
t_{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d_{TLH}	Delta Low to High		0.07		0.08		0.09	ns/pF
d_{THL}	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Output Module Timing[1]								
t_{DLH}	Data to Pad High		10.1		11.5		13.5	ns
t_{DHL}	Data to Pad Low		8.4		9.6		11.2	ns
t_{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t_{ENZL}	Enable Pad Z to Low		11.6		13.2		15.5	ns
t_{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t_{ENLZ}	Enable Pad Low to Z		8.3		9.5		11.1	ns
t_{GLH}	G to Pad High		8.9		10.2		11.9	ns
t_{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d_{TLH}	Delta Low to High		0.12		0.13		0.16	ns/pF
d_{THL}	Delta High to Low		0.09		0.10		0.12	ns/pF

Notes:

1. *Delays based on 50 pF loading.*
2. *SSO information can be found at www.microsemi.com/soc/techdocs/appnotes/board_consideration.aspx.*

A1240A Timing Characteristics

***Table 2-15* • A1240A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

Logic Module Propagation Delays[1]		**–2 Speed[3]**		**–1 Speed**		**Std. Speed**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{PD1}	Single Module		3.8		4.3		5.0	ns
t_{CO}	Sequential Clock to Q		3.8		4.3		5.0	ns
t_{GO}	Latch G to Q		3.8		4.3		5.0	ns
t_{RS}	Flip-Flop (Latch) Reset to Q		3.8		4.3		5.0	ns
Predicted Routing Delays[2]								
t_{RD1}	FO = 1 Routing Delay		1.4		1.5		1.8	ns
t_{RD2}	FO = 2 Routing Delay		1.7		2.0		2.3	ns
t_{RD3}	FO = 3 Routing Delay		2.3		2.6		3.0	ns
t_{RD4}	FO = 4 Routing Delay		3.1		3.5		4.1	ns
t_{RD8}	FO = 8 Routing Delay		4.7		5.4		6.3	ns
Sequential Timing Characteristics[3,4]								
t_{SUD}	Flip-Flop (Latch) Data Input Setup	0.4		0.4		0.5		ns
t_{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Setup	0.8		0.9		1.0		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.5		6.0		6.5		ns
t_{WASYN}	Flip-Flop (Latch) Clock Asynchronous Pulse Width	4.5		6.0		6.5		ns
t_A	Flip-Flop Clock Input Period	9.8		12.0		15.0		ns
t_{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		ns
t_{INSU}	Input Buffer Latch Setup	0.4		0.4		0.5		ns
t_{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		ns
t_{OUTSU}	Output Buffer Latch Setup	0.4		0.4		0.5		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency		100.0		80.0		66.0	MHz

Notes:

1. *For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$—whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*
3. *Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the DirectTime Analyzer utility.*
4. *Setup and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.*

A1240A Timing Characteristics (continued)

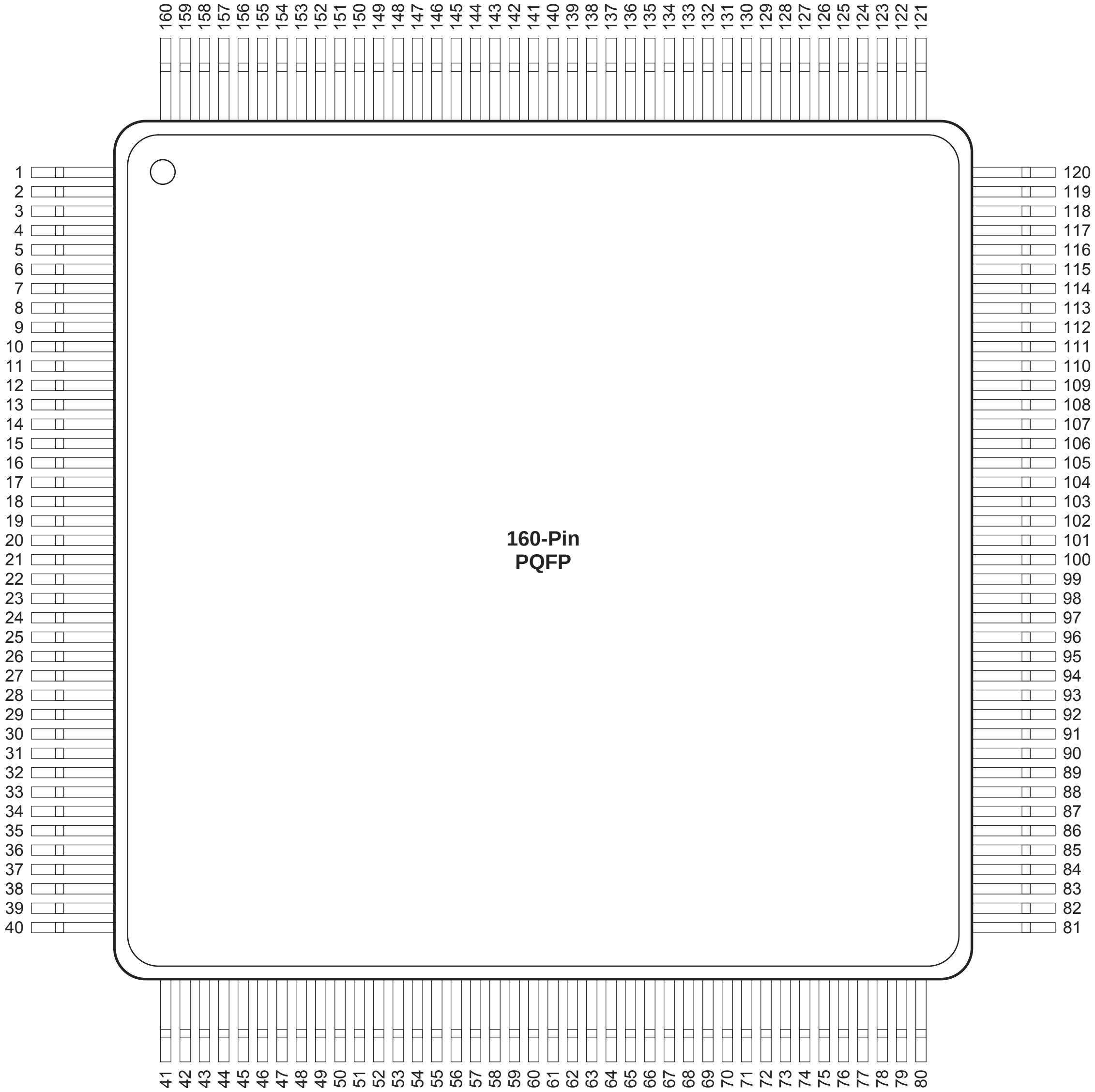
Table 2-17 • **A1240A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

TTL Output Module Timing[1]		**–2 Speed**		**–1 Speed**		**Std. Speed**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{DLH}	Data to Pad High		8.0		9.0		10.6	ns
t_{DHL}	Data to Pad Low		10.1		11.4		13.4	ns
t_{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t_{ENZL}	Enable Pad Z to Low		11.7		13.2		15.5	ns
t_{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t_{ENLZ}	Enable Pad Low to Z		8.4		9.5		11.1	ns
t_{GLH}	G to Pad High		9.0		10.2		11.9	ns
t_{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d_{TLH}	Delta Low to High		0.07		0.08		0.09	ns/pF
d_{THL}	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Output Module Timing[1]								
t_{DLH}	Data to Pad High		10.2		11.5		13.5	ns
t_{DHL}	Data to Pad Low		8.4		9.6		11.2	ns
t_{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t_{ENZL}	Enable Pad Z to Low		11.7		13.2		15.5	ns
t_{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t_{ENLZ}	Enable Pad Low to Z		8.4		9.5		11.1	ns
t_{GLH}	G to Pad High		9.0		10.2		11.9	ns
t_{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d_{TLH}	Delta Low to High		0.12		0.13		0.16	ns/pF
d_{THL}	Delta High to Low		0.09		0.10		0.12	ns/pF

Notes:

1. *Delays based on 50 pF loading.*
2. *SSO information can be found at www.microsemi.com/soc/techdocs/appnotes/board_consideration.aspx.*

PQ160



Note: This is the top view of the package

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

TQ176		
Pin Number	**A1240A Function**	**A1280A Function**
1	GND	GND
2	MODE	MODE
8	NC	NC
10	NC	I/O
11	NC	I/O
13	NC	VCC
18	GND	GND
19	NC	I/O
20	NC	I/O
22	NC	I/O
23	GND	GND
24	NC	VCC
25	VCC	VCC
26	NC	I/O
27	NC	I/O
28	VCC	VCC
29	NC	I/O
33	NC	NC
37	NC	I/O
38	NC	NC
45	GND	GND
52	NC	VCC
54	NC	I/O
55	NC	I/O
57	NC	NC
61	NC	I/O
64	NC	I/O
66	NC	I/O
67	GND	GND
68	VCC	VCC
74	NC	I/O
77	NC	NC
78	NC	I/O
80	NC	I/O

TQ176		
Pin Number	**A1240A Function**	**A1280A Function**
82	NC	VCC
86	NC	I/O
87	SDO	SDO
89	GND	GND
96	NC	I/O
97	NC	I/O
101	NC	NC
103	NC	I/O
106	GND	GND
107	NC	I/O
108	NC	I/O
109	GND	GND
110	VCC	VCC
111	GND	GND
112	VCC	VCC
113	VCC	VCC
114	NC	I/O
115	NC	I/O
116	NC	VCC
121	NC	NC
124	NC	I/O
125	NC	I/O
126	NC	NC
133	GND	GND
135	SDI, I/O	SDI, I/O
136	NC	I/O
140	NC	VCC
143	NC	I/O
144	NC	I/O
145	NC	NC
147	NC	I/O
151	NC	I/O
152	PRA, I/O	PRA, I/O
154	CLKA, I/O	CLKA, I/O

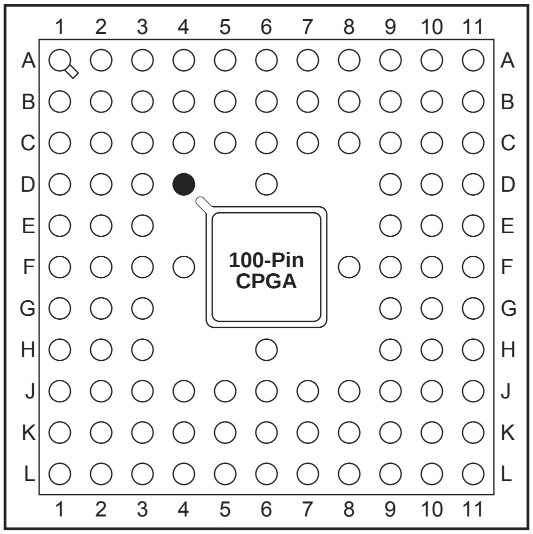
CQ172	
Pin Number	**A1280A Function**
1	MODE
7	GND
12	VCC
17	GND
22	GND
23	VCC
24	VCC
27	VCC
32	GND
37	GND
50	VCC
55	GND
65	GND
66	VCC
75	GND
80	VCC
85	SDO
98	GND
103	GND
106	GND

CQ172	
Pin Number	**A1280A Function**
107	VCC
108	GND
109	VCC
110	VCC
113	VCC
118	GND
123	GND
131	SDI, I/O
136	VCC
141	GND
148	PRA, I/O
150	CLKA, I/O
151	VCC
152	GND
154	CLKB, I/O
156	PRB, I/O
161	GND
166	VCC
171	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PG100



● Orientation Pin

Note

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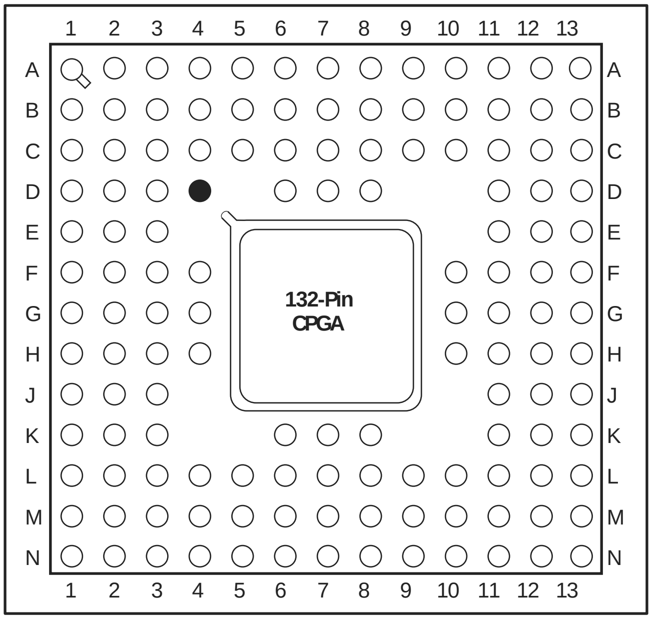
PG132



● Orientation Pin

Note

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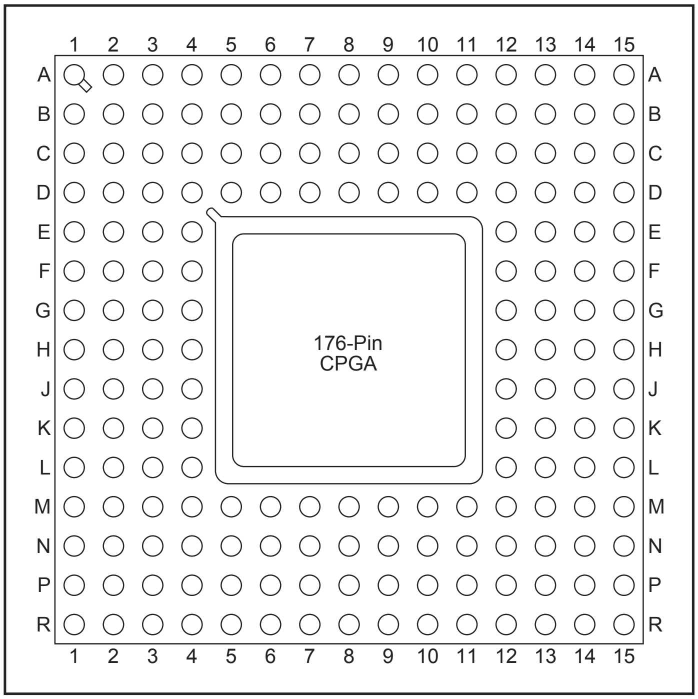
PG176



Note

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Datasheet Categories

Categories

In order to provide the latest information to designers, some datasheet parameters are published before data has been fully characterized from silicon devices. The data provided for a given device is designated as either "Product Brief," "Advance," "Preliminary," or "Production." The definitions of these categories are as follows:

Product Brief

The product brief is a summarized version of a datasheet (advance or production) and contains general product information. This document gives an overview of specific device and family information.

Advance

This version contains initial estimated information based on simulation, other products, devices, or speed grades. This information can be used as estimates, but not for production. This label only applies to the DC and Switching Characteristics chapter of the datasheet and will only be used when the data has not been fully characterized.

Preliminary

The datasheet contains information based on simulation and/or initial characterization. The information is believed to be correct, but changes are possible.

Production

This version contains information that is considered to be final.

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